

Estrada™

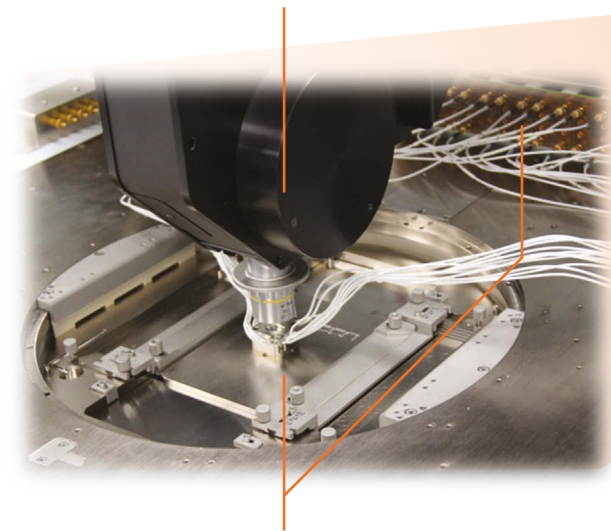
FES: Semi-automated test cell for single-site WLR

CM300xi semi-automated probe station

- Active vibration isolation system and High-Temperature Stability (HTS) platen for long-term contact stability at elevated temperatures
- MicroChamber® shielding for low-noise environment
- Camera-based automatic XYZ and theta wafer alignment to simplify loading
- Locking roll-out stage for safe and convenient handling of 300 mm and smaller/partial wafers

eVue™ microscope and VueTrack technology

- Downward-looking camera for in-situ alignment at temperature
- Camera-based automatic XYZ and theta correction for accurate and repeatable contact when stepping



Single-site Celadon probe card

- Up to 1x32 or 2x16 probes for multiple DUTs in parallel
- High-temperature design for longevity and data integrity
- Patch panels to flexibly re-map SMU signals to probes



20°C - 300°C thermal system

- Broad temperature range for test condition flexibility
- Ultra-flat chuck for stable and repeatable measurements

Conductor test executive software

- Automated testing at multiple touchdown points for high throughput with low operator effort
- Flexible test sequence programming with repeated or different tests at each touchdown to produce large sample sizes and evaluate a broad range of test conditions with a single start

Velox™ prober control software

- Intuitive GUI for efficient system utilization
- Software joystick for precise, sub-micron positioning
- CellView for improved sub-die navigation

Symphony™ reliability test system

- Compact system on prober's rear instrument shelf to minimize floor space
- Scalability and reconfigurability to adapt to changing needs
- Same SMUs and software as 1164 package-level system for combined analysis
- Zeus full-featured, intuitive GUI for reliability test flexibility and quick setup



Constant voltage TDDB and SILC packages

- Up to 30 DUTs in parallel for high throughput
- Multiple Application Module options to test a variety of technologies up to ±150 V / 350 mA per DUT
- True parallel measurements with fast sampling to capture soft breakdown in detail and minimize SILC relaxation

HCI and conventional BTI packages

- Up to eight DUTs in parallel for high throughput
- Multiple Application Module options to test a variety of technologies up to ±150 V / 100 mA per DUT
- Accurate, parallel stress/measure sources for minimized relaxation and high-quality data

©Copyright 2016, Cascade Microtech, Inc. All rights reserved.
Cascade Microtech and MicroChamber are registered trademarks,
and Estrada, Velox, eVue and Symphony are trademarks of
Cascade Microtech, Inc.
All other trademarks are the property of their respective owners.

Data subject to change without notice

Estrada FES-PH-1016

www.cascademicrotech.com

